

**Notice of References Cited**

Application/Control No.

10/517,291

Applicant(s)/Patent Under  
Reexamination  
TOYAMA ET AL.

Examiner

NOAH S. WIESE

Art Unit

1793

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,297,721	03-1994	Schneider et al.	228/180.1
*	B	US-6,800,345	10-2004	Teshima et al.	428/35.8
*	C	US-6,548,460	04-2003	Higai et al.	508/465
*	D	US-4,413,084	11-1983	Horvath, Stanley K.	524/315
*	E	US-2002/0139277	10-2002	Ogata, Hitoshi	106/31.3
*	F	US-6,099,968	08-2000	Harakawa et al.	428/414
*	G	US-5,450,666	09-1995	Conn et al.	29/890.043
*	H	US-3,607,369	09-1971	Batta, Louis Bela	427/309
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.